

Title: PROBE TESTING METHOD AND
APPARATUS FOR DETERMINING
ACCEPTABLE/DEFECTIVE END SHAPE OF
CONTACT PROBE THROUGH IMAGE
ANALYSIS

Inventor(s): Yoshihiro SASAKI, et al.
DOCKET NO.: 040373-0338

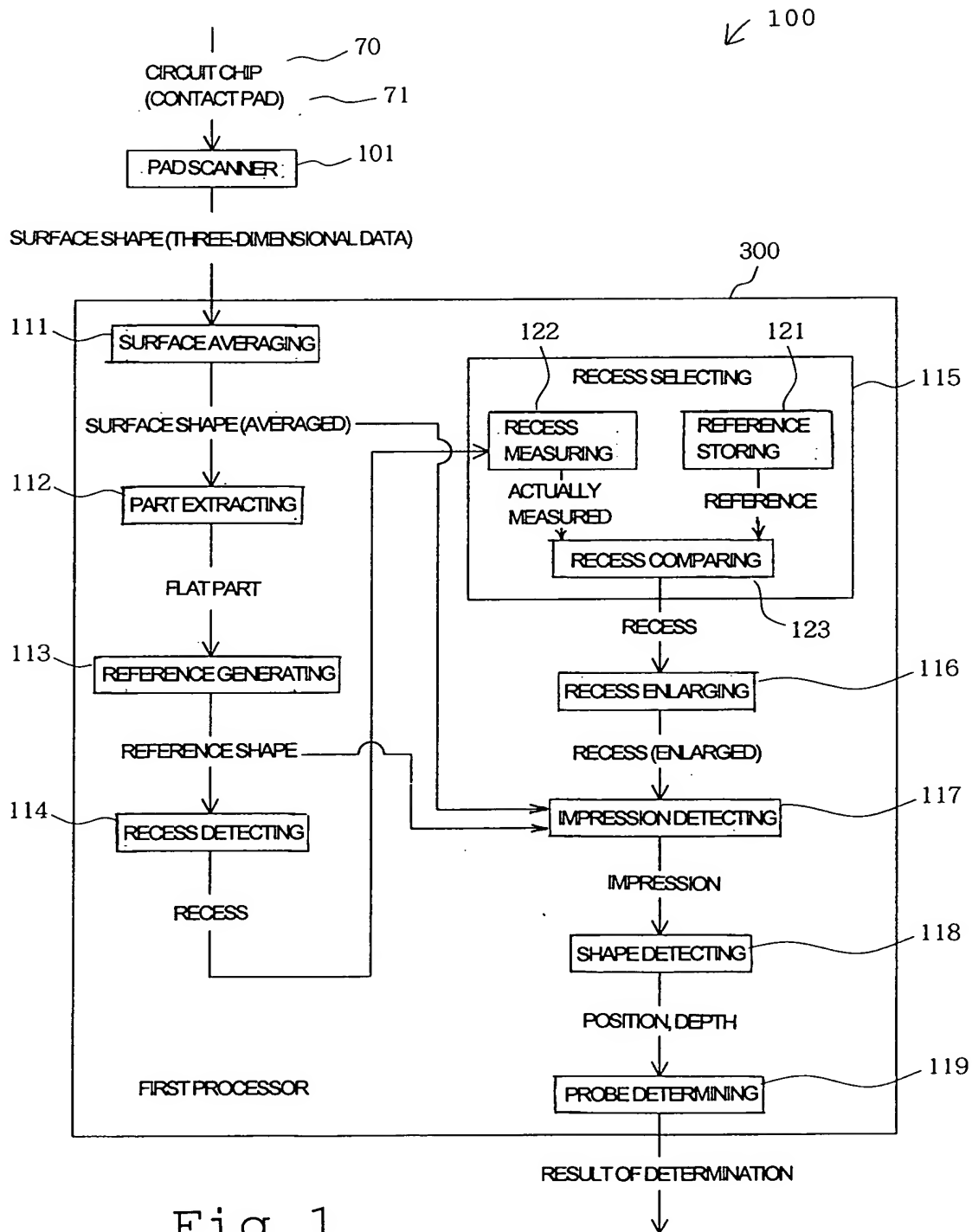
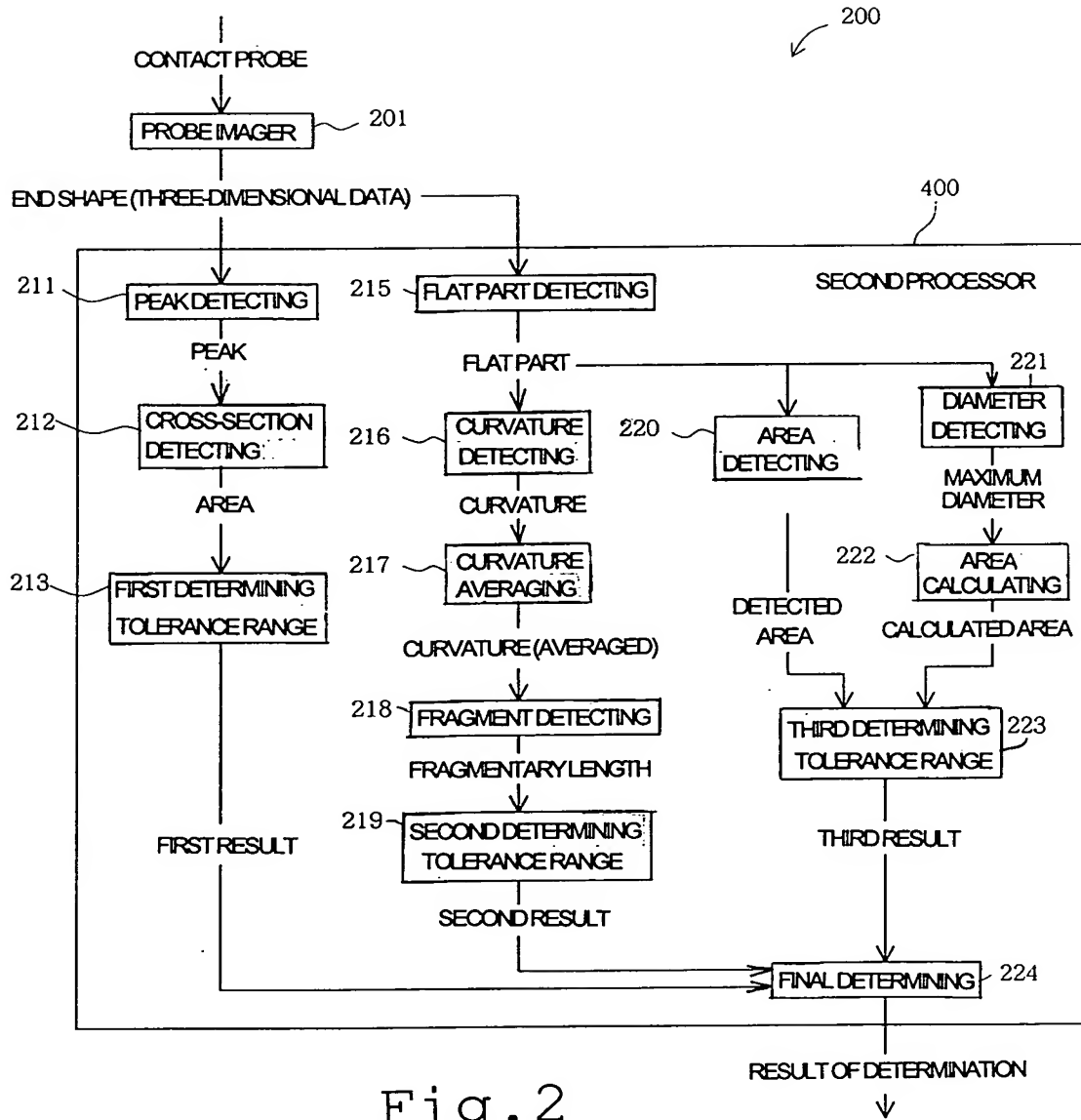


Fig.1

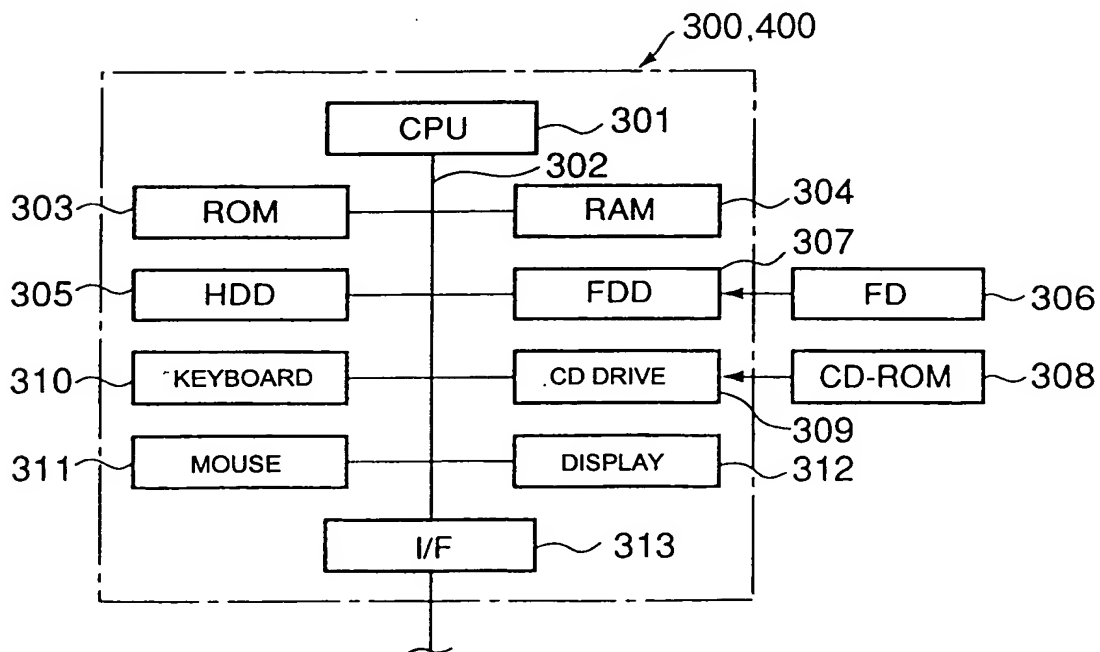
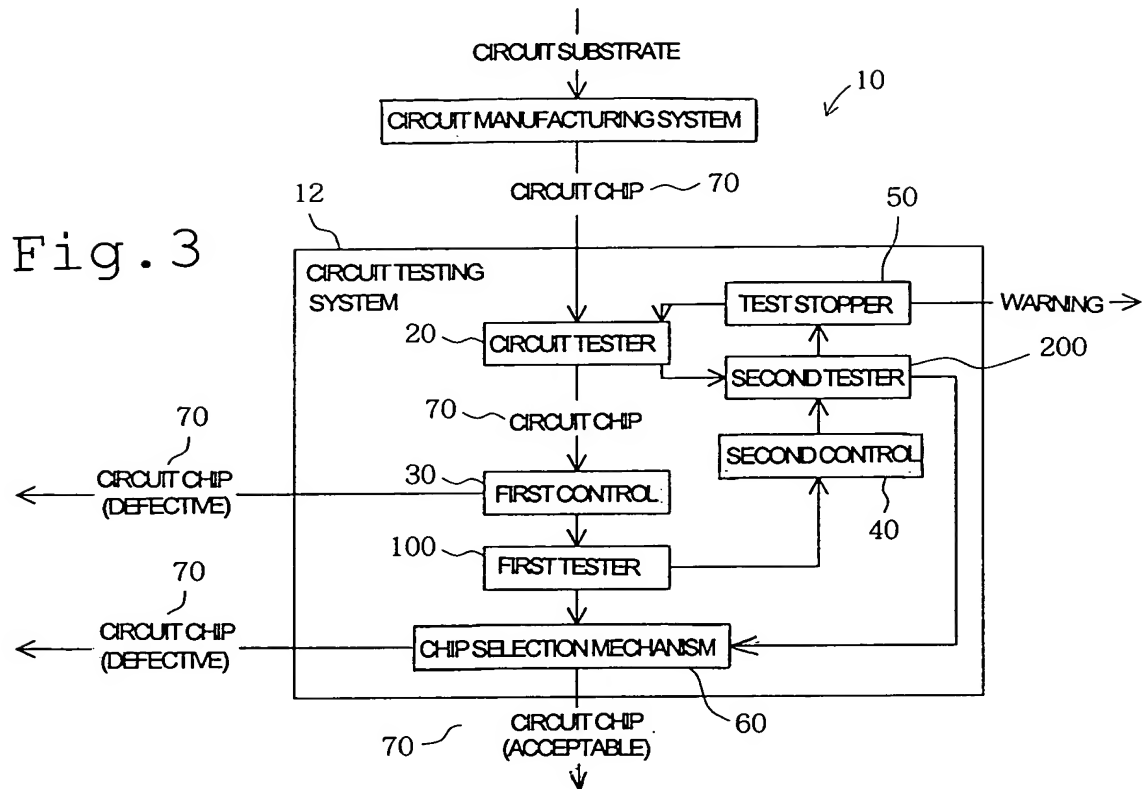
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Fig. 5a

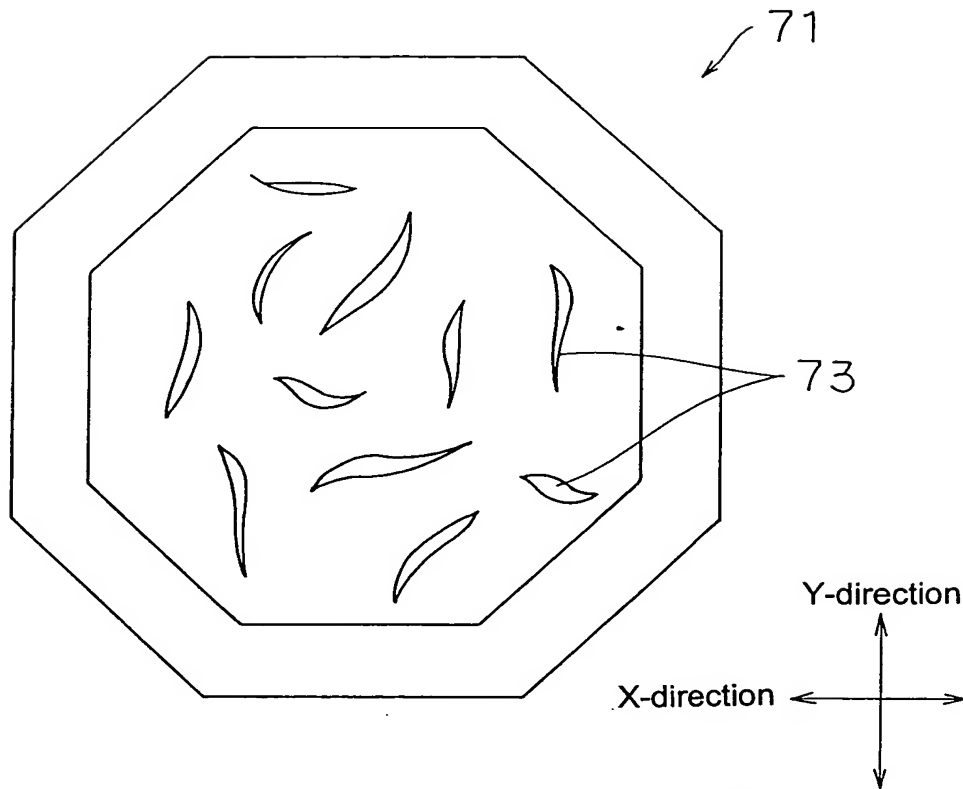
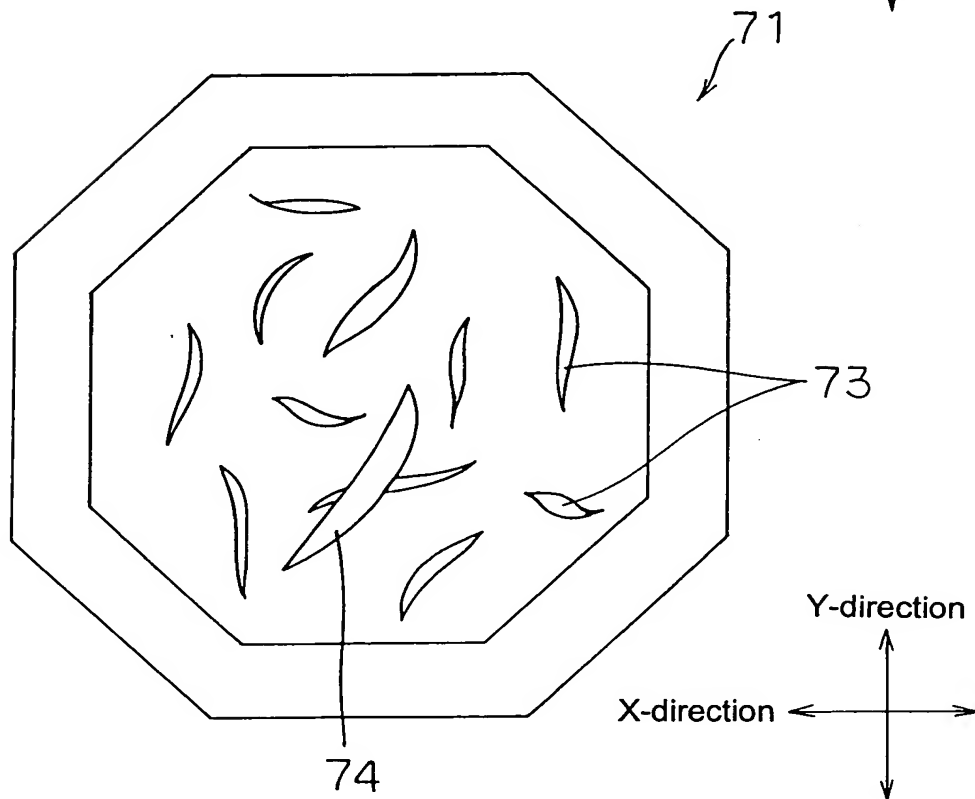


Fig. 5b



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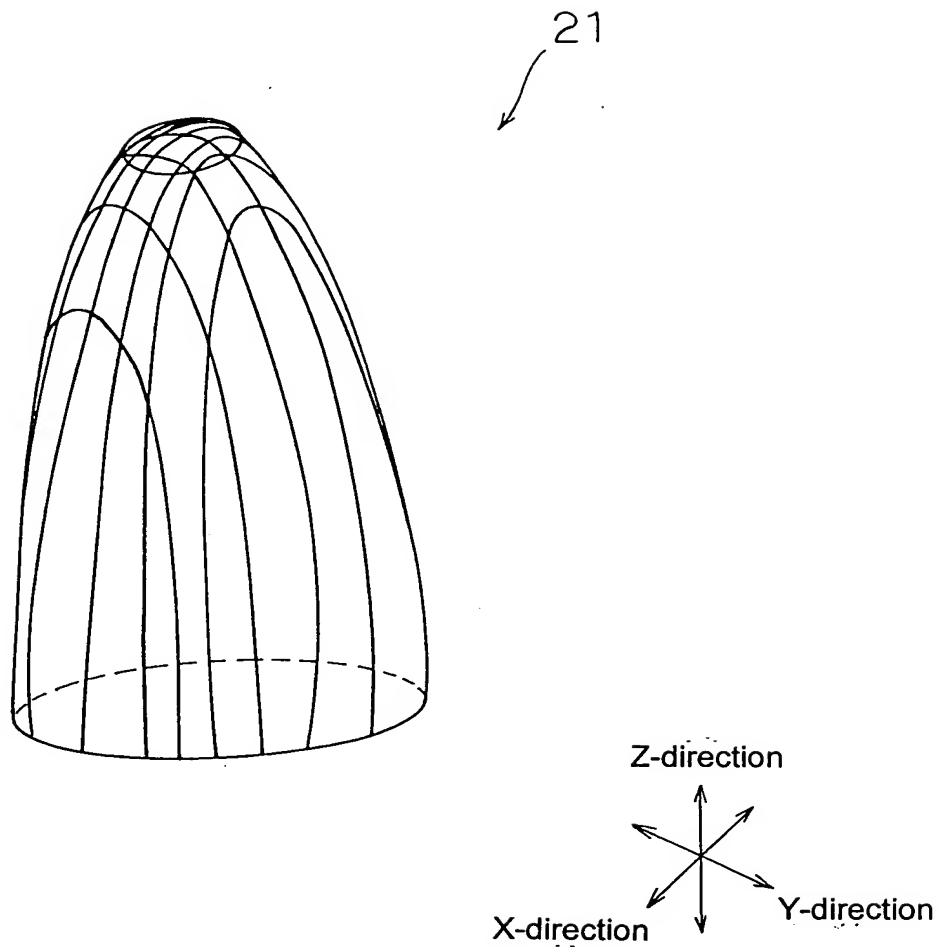


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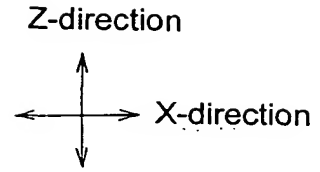


Fig. 7a



Fig. 7b

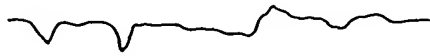


Fig. 7c

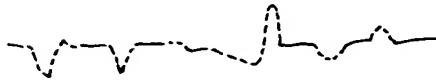


Fig. 7d



Fig. 7e



Fig. 7f



Fig. 7g



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Fig. 8a

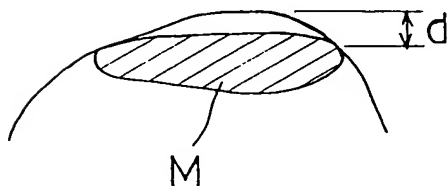


Fig. 8b



Fig. 9a

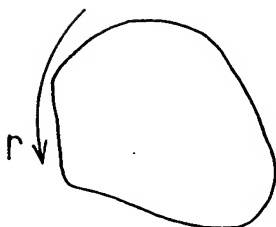


Fig. 9b

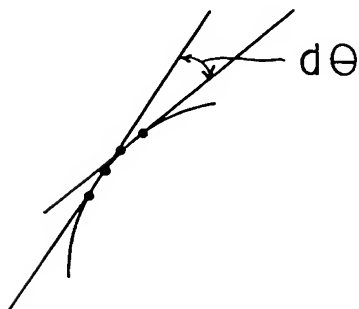
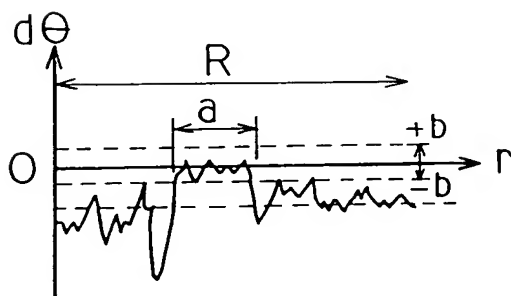


Fig. 9c



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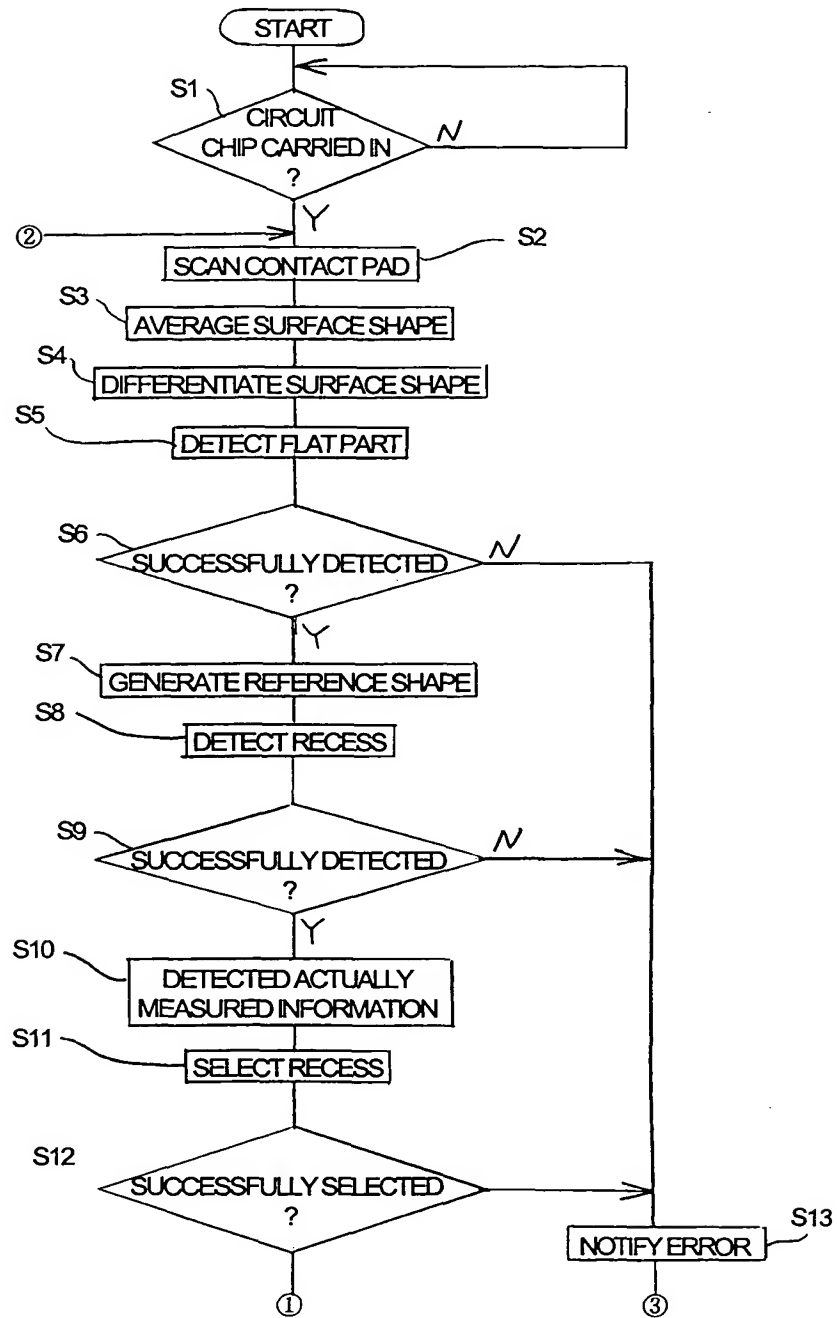


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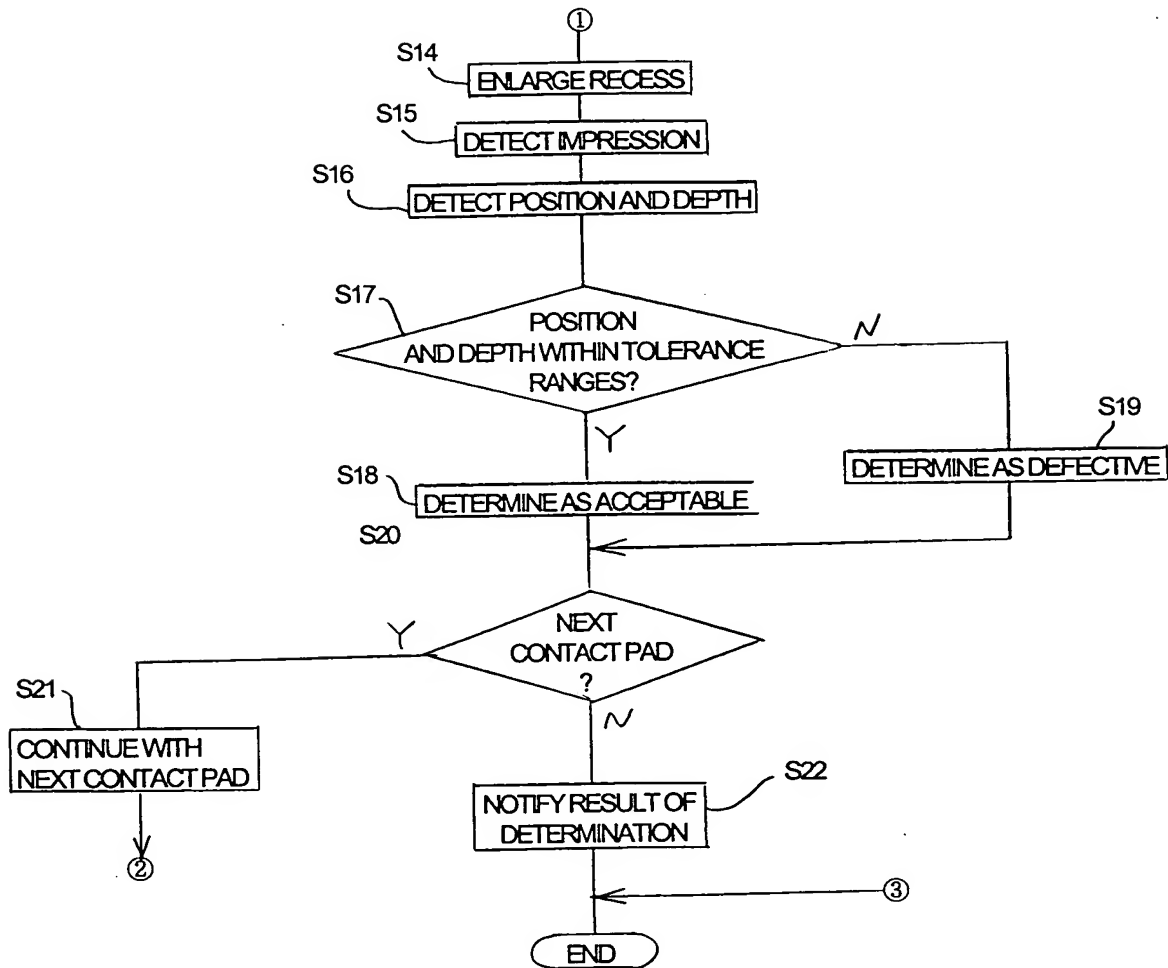


Fig.11

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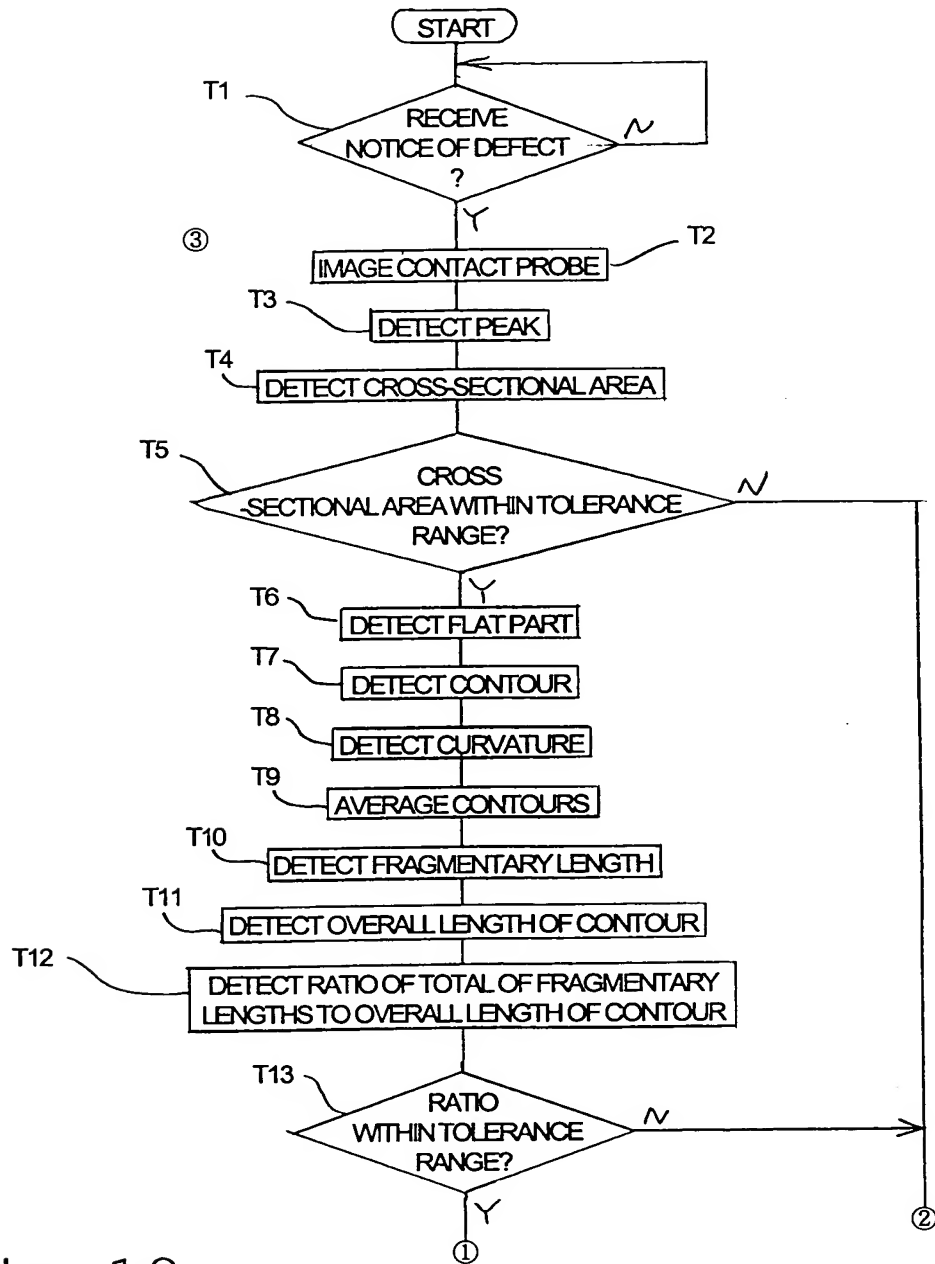


Fig.12

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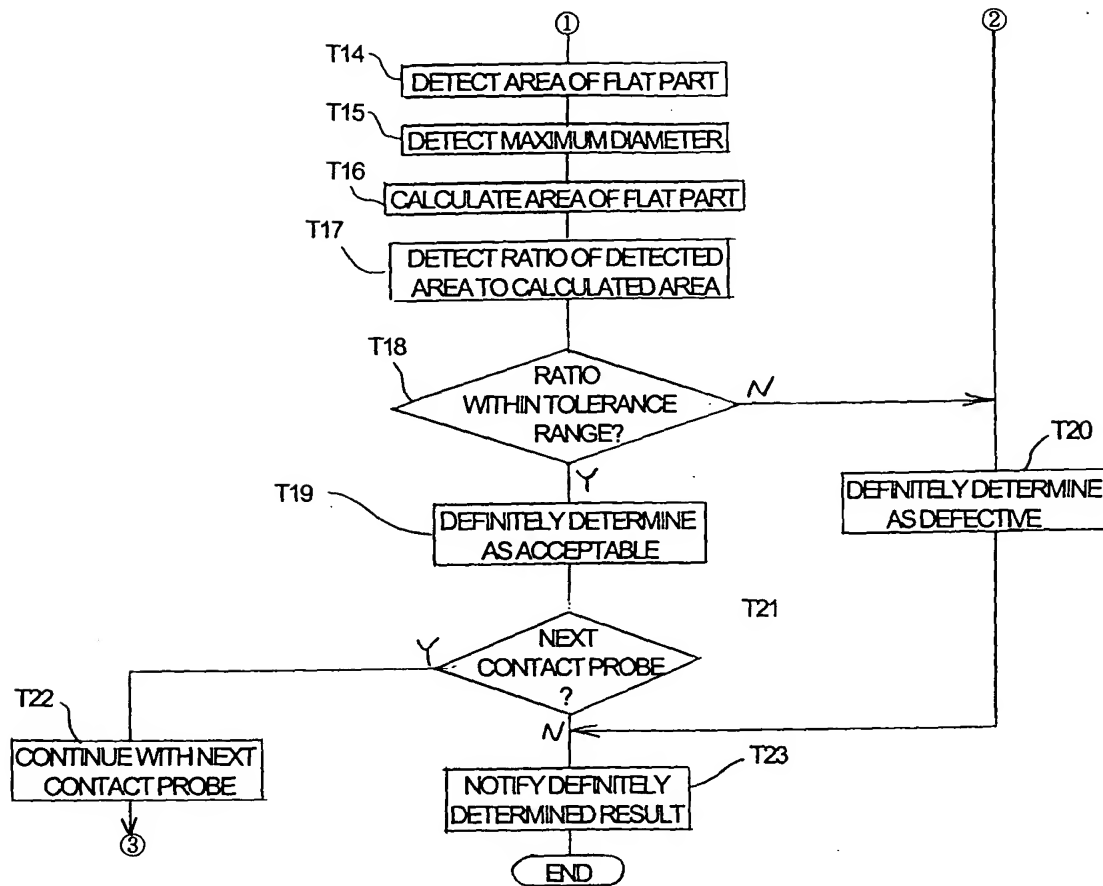


Fig.13